## Applicant(s)/Patent Under Application/Control No. Reexamination 10/560,313 SHIBA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2821 Ephrem Alemu **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 01-2004 US-2004/0004441 Yano, Hidetoshi 315/169.1 Α 315/276 09-2004 Hiraoka et al. US-6,788,008 В 11-2003 Okamoto et al. 315/246 US-6,646,391 С 03-2002 315/209R US-6,356,033 Okamoto et al. D US-Ε US-F US-G USн US-١ US-US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) ٧ W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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